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Freescale Semiconductor Technical Data

MPC860EC Rev. 10, 09/2015

MPC860 PowerQUICC Family Hardware Specifications

This hardware specification contains detailed information on power considerations, DC/AC electrical characteristics, and AC timing specifications for the MPC860 family.

To locate published errata or updates for this document, see the MPC860 product summary page on the website listed on the back cover of this document or contact your local Freescale sales office.

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Freescale reserves the right to change the detail specifications as may be required to permit improvements in the design of its products.





Overview

1 Overview

The MPC860 power quad integrated communications controller (PowerQUICCTM) is a versatile one-chip integrated microprocessor and peripheral combination designed for a variety of controller applications. It particularly excels in communications and networking systems. The PowerQUICC unit is referred to as the MPC860 in this hardware specification.

The MPC860 implements Power ArchitectureTM technology and contains a superset of Freescale's MC68360 quad integrated communications controller (QUICC), referred to here as the QUICC, RISC communications processor module (CPM). The CPU on the MPC860 is a 32-bit core built on Power Architecture technology that incorporates memory management units (MMUs) and instruction and data caches.. The CPM from the MC68360 QUICC has been enhanced by the addition of the inter-integrated controller (I²C) channel. The memory controller has been enhanced, enabling the MPC860 to support any type of memory, including high-performance memories and new types of DRAMs. A PCMCIA socket controller supports up to two sockets. A real-time clock has also been integrated.

Table 1 shows the functionality supported by the MPC860 family.

Part	Cache ((Kbytes)	Ethe	ernet			
	Instruction Cache	Data Cache	10T	10/100	ATM	SCC	Reference ¹
MPC860DE	4	4	Up to 2	_	_	2	1
MPC860DT	4	4	Up to 2	1	Yes	2	1
MPC860DP	16	8	Up to 2	1	Yes	2	1
MPC860EN	4	4	Up to 4	_	_	4	1
MPC860SR	4	4	Up to 4	_	Yes	4	1
MPC860T	4	4	Up to 4	1	Yes	4	1
MPC860P	16	8	Up to 4	1	Yes	4	1
MPC855T	4	4	1	1	Yes	1	2

Table 1. MPC860 Family Functionality

¹ Supporting documentation for these devices refers to the following:

^{1.} MPC860 PowerQUICC Family User's Manual (MPC860UM, Rev. 3)

^{2.} MPC855T User's Manual (MPC855TUM, Rev. 1)



2 Features

The following list summarizes the key MPC860 features:

- Embedded single-issue, 32-bit core (implementing the Power Architecture technology) with thirty-two 32-bit general-purpose registers (GPRs)
 - The core performs branch prediction with conditional prefetch without conditional execution.
 - 4- or 8-Kbyte data cache and 4- or 16-Kbyte instruction cache (see Table 1)
 - 16-Kbyte instruction caches are four-way, set-associative with 256 sets; 4-Kbyte instruction caches are two-way, set-associative with 128 sets.
 - 8-Kbyte data caches are two-way, set-associative with 256 sets; 4-Kbyte data caches are two-way, set-associative with 128 sets.
 - Cache coherency for both instruction and data caches is maintained on 128-bit (4-word) cache blocks.
 - Caches are physically addressed, implement a least recently used (LRU) replacement algorithm, and are lockable on a cache block basis.
 - MMUs with 32-entry TLB, fully-associative instruction, and data TLBs
 - MMUs support multiple page sizes of 4-, 16-, and 512-Kbytes, and 8-Mbytes; 16 virtual address spaces and 16 protection groups
 - Advanced on-chip-emulation debug mode
- Up to 32-bit data bus (dynamic bus sizing for 8, 16, and 32 bits)
- 32 address lines
- Operates at up to 80 MHz
- Memory controller (eight banks)
 - Contains complete dynamic RAM (DRAM) controller
 - Each bank can be a chip select or \overline{RAS} to support a DRAM bank.
 - Up to 15 wait states programmable per memory bank
 - Glueless interface to DRAM, SIMMS, SRAM, EPROM, Flash EPROM, and other memory devices
 - DRAM controller programmable to support most size and speed memory interfaces
 - Four \overline{CAS} lines, four \overline{WE} lines, and one \overline{OE} line
 - Boot chip-select available at reset (options for 8-, 16-, or 32-bit memory)
 - Variable block sizes (32 Kbytes to 256 Mbytes)
 - Selectable write protection
 - On-chip bus arbitration logic
- General-purpose timers
 - Four 16-bit timers or two 32-bit timers
 - Gate mode can enable/disable counting
 - Interrupt can be masked on reference match and event capture.



Features

- System integration unit (SIU)
 - Bus monitor
 - Software watchdog
 - Periodic interrupt timer (PIT)
 - Low-power stop mode
 - Clock synthesizer
 - Decrementer, time base, and real-time clock (RTC)
 - Reset controller
 - IEEE 1149.1TM Std. test access port (JTAG)
- Interrupts
 - Seven external interrupt request (IRQ) lines
 - 12 port pins with interrupt capability
 - 23 internal interrupt sources
 - Programmable priority between SCCs
 - Programmable highest priority request
- 10/100 Mbps Ethernet support, fully compliant with the IEEE 802.3u® Standard (not available when using ATM over UTOPIA interface)
- ATM support compliant with ATM forum UNI 4.0 specification
 - Cell processing up to 50–70 Mbps at 50-MHz system clock
 - Cell multiplexing/demultiplexing
 - Support of AAL5 and AAL0 protocols on a per-VC basis. AAL0 support enables OAM and software implementation of other protocols.
 - ATM pace control (APC) scheduler, providing direct support for constant bit rate (CBR) and unspecified bit rate (UBR) and providing control mechanisms enabling software support of available bit rate (ABR)
 - Physical interface support for UTOPIA (10/100-Mbps is not supported with this interface) and byte-aligned serial (for example, T1/E1/ADSL)
 - UTOPIA-mode ATM supports level-1 master with cell-level handshake, multi-PHY (up to four physical layer devices), connection to 25-, 51-, or 155-Mbps framers, and UTOPIA/system clock ratios of 1/2 or 1/3.
 - Serial-mode ATM connection supports transmission convergence (TC) function for T1/E1/ADSL lines, cell delineation, cell payload scrambling/descrambling, automatic idle/unassigned cell insertion/stripping, header error control (HEC) generation, checking, and statistics.
- Communications processor module (CPM)
 - RISC communications processor (CP)
 - Communication-specific commands (for example, GRACEFUL STOP TRANSMIT, ENTER HUNT MODE, and RESTART TRANSMIT)
 - Supports continuous mode transmission and reception on all serial channels



- Up to 8 Kbytes of dual-port RAM
- 16 serial DMA (SDMA) channels
- Three parallel I/O registers with open-drain capability
- Four baud-rate generators (BRGs)
 - Independent (can be tied to any SCC or SMC)
 - Allows changes during operation
 - Autobaud support option
- Four serial communications controllers (SCCs)
 - Ethernet/IEEE 802.3® standard optional on SCC1–4, supporting full 10-Mbps operation (available only on specially programmed devices)
 - HDLC/SDLC (all channels supported at 2 Mbps)
 - HDLC bus (implements an HDLC-based local area network (LAN))
 - Asynchronous HDLC to support point-to-point protocol (PPP)
 - AppleTalk
 - Universal asynchronous receiver transmitter (UART)
 - Synchronous UART
 - Serial infrared (IrDA)
 - Binary synchronous communication (BISYNC)
 - Totally transparent (bit streams)
 - Totally transparent (frame-based with optional cyclic redundancy check (CRC))
- Two SMCs (serial management channels)
 - UART
 - Transparent
 - General circuit interface (GCI) controller
 - Can be connected to the time-division multiplexed (TDM) channels
- One SPI (serial peripheral interface)
 - Supports master and slave modes
 - Supports multimaster operation on the same bus
- One I²C (inter-integrated circuit) port
 - Supports master and slave modes
 - Multiple-master environment support
- Time-slot assigner (TSA)
 - Allows SCCs and SMCs to run in multiplexed and/or non-multiplexed operation
 - Supports T1, CEPT, PCM highway, ISDN basic rate, ISDN primary rate, user defined
 - 1- or 8-bit resolution
 - Allows independent transmit and receive routing, frame synchronization, and clocking



Features

- Allows dynamic changes
- Can be internally connected to six serial channels (four SCCs and two SMCs)
- Parallel interface port (PIP)
 - Centronics interface support
 - Supports fast connection between compatible ports on the MPC860 or the MC68360
- PCMCIA interface
 - Master (socket) interface, release 2.1 compliant
 - Supports two independent PCMCIA sockets
 - Supports eight memory or I/O windows
- Low power support
 - Full on—all units fully powered
 - Doze—core functional units disabled except time base decrementer, PLL, memory controller, RTC, and CPM in low-power standby
 - Sleep—all units disabled except RTC and PIT, PLL active for fast wake up
 - Deep sleep—all units disabled including PLL except RTC and PIT
 - Power down mode—all units powered down except PLL, RTC, PIT, time base, and decrementer
- Debug interface
 - Eight comparators: four operate on instruction address, two operate on data address, and two operate on data
 - Supports conditions: $= \neq < >$
 - Each watchpoint can generate a break-point internally.
- 3.3-V operation with 5-V TTL compatibility except EXTAL and EXTCLK
- 357-pin ball grid array (BGA) package



3 Maximum Tolerated Ratings

This section provides the maximum tolerated voltage and temperature ranges for the MPC860. Table 2 provides the maximum ratings.

This device contains circuitry protecting against damage due to high-static voltage or electrical fields; however, it is advised that normal precautions be taken to avoid application of any voltages higher than maximum-rated voltages to this high-impedance circuit. Reliability of operation is enhanced if unused inputs are tied to an appropriate logic voltage level (for example, either GND or V_{DD}).

Table 2. Maximum Tolerated Ratings

(GND = 0 V)

Rating	Symbol	Value	Unit
Supply voltage ¹	V_{DDH}	-0.3 to 4.0	V
	V _{DDL}	-0.3 to 4.0	V
	KAPWR	-0.3 to 4.0	V
	V _{DDSYN}	-0.3 to 4.0	V
Input voltage ²	V _{in}	GND – 0.3 to V _{DDH}	V
Temperature ³ (standard)	T _{A(min)}	0	°C
	T _{j(max)}	95	°C
Temperature ³ (extended)	T _{A(min)}	-40	°C
	T _{j(max)}	95	°C
Storage temperature range	T _{stg}	-55 to 150	°C

¹ The power supply of the device must start its ramp from 0.0 V.

Functional operating conditions are provided with the DC electrical specifications in Table 6. Absolute maximum ratings are stress ratings only; functional operation at the maxima is not guaranteed. Stress beyond those listed may affect device reliability or cause permanent damage to the device.

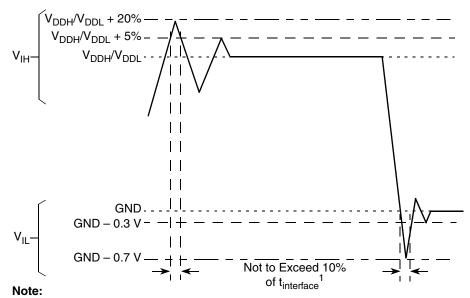
Caution: All inputs that tolerate 5 V cannot be more than 2.5 V greater than the supply voltage. This restriction applies to power-up and normal operation (that is, if the MPC860 is unpowered, voltage greater than 2.5 V must not be applied to its inputs).

³ Minimum temperatures are guaranteed as ambient temperature, T_A. Maximum temperatures are guaranteed as junction temperature, T_j.



Thermal Characteristics

Figure 1 shows the undershoot and overshoot voltages at the interface of the MPC860.



^{1.} $t_{\text{interface}}$ refers to the clock period associated with the bus clock interface.

Figure 1. Undershoot/Overshoot Voltage for V_{DDH} and V_{DDL}

4 Thermal Characteristics

Table 3. Package Description

Package Designator	Package Code (Case No.)	Package Description
ZP	5050 (1103-01)	PBGA 357 25*25*0.9P1.27
ZQ/VR	5058 (1103D-02)	PBGA 357 25*25*1.2P1.27



Table 4 shows the thermal characteristics for the MPC860.

Table 4. MPC860 Thermal Resistance Data

Rating	Env	vironment	Symbol	ZP MPC860P	ZQ / VR MPC860P	Unit
Mold Compound Thickne	ss			0.85	1.15	mm
Junction-to-ambient ¹	Natural convection	Single-layer board (1s)	$R_{\theta JA}^2$	34	34	°C/W
		Four-layer board (2s2p)	$R_{\theta JMA}^3$	22	22	
	Airflow (200 ft/min)	Single-layer board (1s)	$R_{\theta JMA}^3$	27	27	
		Four-layer board (2s2p)	$R_{\theta JMA}^3$	18	18	
Junction-to-board 4		•	$R_{\theta JB}$	14	13	
Junction-to-case 5			$R_{\theta JC}$	6	8	
Junction-to-package top	Natural convection		Ψ_{JT}	2	2	

Junction temperature is a function of on-chip power dissipation, package thermal resistance, mounting site (board) temperature, ambient temperature, airflow, power dissipation of other components on the board, and board thermal resistance

² Per SEMI G38-87 and JEDEC JESD51-2 with the single-layer board horizontal.

³ Per JEDEC JESD51-6 with the board horizontal.

⁴ Thermal resistance between the die and the printed-circuit board per JEDEC JESD51-8. Board temperature is measured on the top surface of the board near the package.

Indicates the average thermal resistance between the die and the case top surface as measured by the cold plate method (MIL SPEC-883 Method 1012.1) with the cold plate temperature used for the case temperature. For exposed pad packages where the pad would be expected to be soldered, junction-to-case thermal resistance is a simulated value from the junction to the exposed pad without contact resistance.

⁶ Thermal characterization parameter indicating the temperature difference between the package top and the junction temperature per JEDEC JESD51-2.



Power Dissipation

5 Power Dissipation

Table 5 provides power dissipation information. The modes are 1:1, where CPU and bus speeds are equal, and 2:1, where CPU frequency is twice the bus speed.

Table 5. Power Dissipation (P_D)

Die Revision	Frequency (MHz)	Typical ¹	Maximum ²	Unit
D.4	50	656	735	mW
(1:1 mode)	66	TBD	TBD	mW
D.4	66	722	762	mW
(2:1 mode)	80	851	909	mW

¹ Typical power dissipation is measured at 3.3 V.

NOTE

Values in Table 5 represent V_{DDL} -based power dissipation and do not include I/O power dissipation over V_{DDH} . I/O power dissipation varies widely by application due to buffer current, depending on external circuitry.

6 DC Characteristics

Table 6 provides the DC electrical characteristics for the MPC860.

Table 6. DC Electrical Specifications

Characteristic	Symbol	Min	Max	Unit
Operating voltage at 40 MHz or less	V _{DDH} , V _{DDL} , V _{DDSYN}	3.0	3.6	V
	KAPWR (power-down mode)	2.0	3.6	V
	KAPWR (all other operating modes)	V _{DDH} – 0.4	V _{DDH}	V
Operating voltage greater than 40 MHz	$V_{ m DDH}, V_{ m DDL}, { m KAPWR}, \ V_{ m DDSYN}$	3.135	3.465	V
	KAPWR (power-down mode)	2.0	3.6	V
	KAPWR (all other operating modes)	V _{DDH} – 0.4	V _{DDH}	V
Input high voltage (all inputs except EXTAL and EXTCLK)	V _{IH}	2.0	5.5	V
Input low voltage ¹	V _{IL}	GND	0.8	V
EXTAL, EXTCLK input high voltage	V _{IHC}	0.7 × (V _{DDH})	V _{DDH} + 0.3	V
Input leakage current, V_{in} = 5.5 V (except TMS, \overline{TRST} , DSCK, and DSDI pins)	l _{in}	_	100	μА

² Maximum power dissipation is measured at 3.5 V.



Table 6. DC Electrical Specifications (continued)

Characteristic	Symbol	Min	Max	Unit
Input leakage current, $V_{in} = 3.6 \text{ V}$ (except TMS, $\overline{\text{TRST}}$, DSCK, and DSDI pins)	I _{In}	_	10	μА
Input leakage current, V _{in} = 0 V (except TMS, TRST, DSCK, and DSDI pins)	I _{In}	_	10	μА
Input capacitance ²	C _{in}	_	20	pF
Output high voltage, I _{OH} = -2.0 mA, V _{DDH} = 3.0 V (except XTAL, XFC, and open-drain pins)	V _{OH}	2.4	_	V
Output low voltage $\begin{split} &I_{OL}=2.0\text{ mA, CLKOUT}\\ &I_{OL}=3.2\text{ mA} \stackrel{3}{\text{1}}\\ &I_{OL}=5.3\text{ mA} \stackrel{4}{\text{1}}\\ &I_{OL}=7.0\text{ mA, TXD1/PA14, TXD2/PA12}\\ &I_{OL}=8.9\text{ mA, }\overline{\text{TS, }}\overline{\text{TA, }}\overline{\text{TEA, }}\overline{\text{BI, BB, HRESET, }}\overline{\text{SRESET}} \end{split}$	V _{OL}	_	0.5	V

¹ V_{II} (max) for the I²C interface is 0.8 V rather than the 1.5 V as specified in the I²C standard.

² Input capacitance is periodically sampled.

³ A(0:31), TSIZO/REG, TSIZ1, D(0:31), DP(0:3)/IRQ(3:6), RD/WR, BURST, RSV/IRQ2, IP_B(0:1)/IWP(0:1)/VFLS(0:1), IP_B2/IOIS16_B/AT2, IP_B3/IWP2/VF2, IP_B4/LWP0/VF0, IP_B5/LWP1/VF1, IP_B6/DSDI/AT0, IP_B7/PTR/AT3, RXD1/PA15, RXD2/PA13, L1TXDB/PA11, L1RXDB/PA10, L1TXDA/PA9, L1RXDA/PA8, TIN1/L1RCLKA/BRGO1/CLK1/PA7, BRGCLK1/TOUT1/CLK2/PA6, TIN2/L1TCLKA/BRGO2/CLK3/PA5, TOUT2/CLK4/PA4, TIN3/BRGO3/CLK5/PA3, BRGCLK2/L1RCLKB/TOUT3/CLK6/PA2, TIN4/BRGO4/CLK7/PA1, L1TCLKB/TOUT4/CLK8/PA0, REJCT1/SPISEL/PB31, SPICLK/PB30,SPIMOSI/PB29, BRGO4/SPIMISO/PB28, BRGO1/I2CSDA/PB27, BRGO2/I2CSCL/PB26, SMTXD1/PB25, SMRXD1/PB24, SMSYN1/SDACK1/PB23, SMSYN2/SDACK2/PB22, SMTXD2/L1CLKOB/PB21, SMRXD2/L1CLKOA/PB20, L1ST1/RTS1/PB19, L1ST2/RTS2/PB18, L1ST3/L1RQB/PB17, L1ST4/L1RQA/PB16, BRGO3/PB15, RSTRT1/PB14, L1ST1/RTS1/DREQ0/PC15, L1ST2/RTS2/DREQ1/PC14, L1ST3/L1RQB/PC13, L1ST4/L1RQA/PC12, CTS1/PC11, TGATE1/CD1/PC10, CTS2/PC9, TGATE2/CD2/PC8, SDACK2/L1TSYNCB/PC7, L1RSYNCB/PC6, SDACK1/L1TSYNCA/PC5, L1RSYNCA/PC4, PD15, PD14, PD13, PD12, PD11, PD10, PD9, PD8, PD5, PD6, PD7, PD4, PD3, MII_MDC, MII_TX_ER, MII_EN, MII_MDIO, and MII_TXD[0:3]

⁴ BDIP/GPL_B(5), BR, BG, FRZ/IRQ6, CS(0:5), CS(6)/CE(1)_B, CS(7)/CE(2)_B, WE0/BS_B0/IORD, WE1/BS_B1/IOWR, WE2/BS_B2/PCOE, WE3/BS_B3/PCWE, BS_A(0:3), GPL_A0/GPL_B0, OE/GPL_A1/GPL_B1, GPL_A(2:3)/GPL_B(2:3)/CS(2:3), UPWAITA/GPL_A4, UPWAITB/GPL_B4, GPL_A5, ALE_A, CE1_A, CE2_A, ALE_B/DSCK/AT1, OP(0:1), OP2/MODCK1/STS, OP3/MODCK2/DSDO, and BADDR(28:30)

Thermal Calculation and Measurement

7 Thermal Calculation and Measurement

For the following discussions, $P_D = (V_{DD} \times I_{DD}) + PI/O$, where PI/O is the power dissipation of the I/O drivers.

7.1 Estimation with Junction-to-Ambient Thermal Resistance

An estimation of the chip junction temperature, T_I , in °C can be obtained from the equation:

$$T_I = T_A + (R_{\theta IA} \times P_D)$$

where:

 T_A = ambient temperature (°C)

 $R_{\theta JA}$ = package junction-to-ambient thermal resistance (°C/W)

 P_D = power dissipation in package

The junction-to-ambient thermal resistance is an industry standard value which provides a quick and easy estimation of thermal performance. However, the answer is only an estimate; test cases have demonstrated that errors of a factor of two (in the quantity $T_I - T_A$) are possible.

7.2 Estimation with Junction-to-Case Thermal Resistance

Historically, the thermal resistance has frequently been expressed as the sum of a junction-to-case thermal resistance and a case-to-ambient thermal resistance:

$$R_{\theta JA} = R_{\theta JC} + R_{\theta CA}$$

where:

 $R_{\theta JA}$ = junction-to-ambient thermal resistance (°C/W)

 $R_{\theta JC}$ = junction-to-case thermal resistance (°C/W)

 $R_{\theta CA}$ = case-to-ambient thermal resistance (°C/W)

 $R_{\theta JC}$ is device related and cannot be influenced by the user. The user adjusts the thermal environment to affect the case-to-ambient thermal resistance, $R_{\theta CA}$. For instance, the user can change the airflow around the device, add a heat sink, change the mounting arrangement on the printed-circuit board, or change the thermal dissipation on the printed-circuit board surrounding the device. This thermal model is most useful for ceramic packages with heat sinks where some 90% of the heat flows through the case and the heat sink to the ambient environment. For most packages, a better model is required.

7.3 Estimation with Junction-to-Board Thermal Resistance

A simple package thermal model which has demonstrated reasonable accuracy (about 20%) is a two-resistor model consisting of a junction-to-board and a junction-to-case thermal resistance. The junction-to-case thermal resistance covers the situation where a heat sink is used or where a substantial amount of heat is dissipated from the top of the package. The junction-to-board thermal resistance describes the thermal performance when most of the heat is conducted to the printed-circuit board. It has been observed that the thermal performance of most plastic packages, especially PBGA packages, is strongly dependent on the board temperature; see Figure 2.



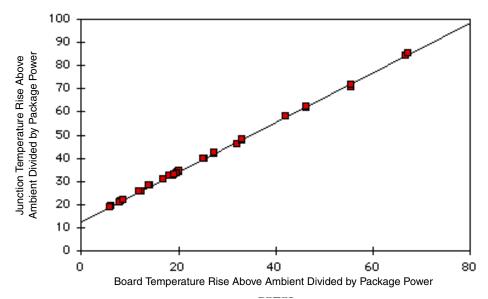


Figure 2. Effect of Board Temperature Rise on Thermal Behavior

If the board temperature is known, an estimate of the junction temperature in the environment can be made using the following equation:

$$T_I = T_B + (R_{\theta IB} \times P_D)$$

where:

 $R_{\theta JB}$ = junction-to-board thermal resistance (°C/W)

 T_B = board temperature (°C)

 P_D = power dissipation in package

If the board temperature is known and the heat loss from the package case to the air can be ignored, acceptable predictions of junction temperature can be made. For this method to work, the board and board mounting must be similar to the test board used to determine the junction-to-board thermal resistance, namely a 2s2p (board with a power and a ground plane) and by attaching the thermal balls to the ground plane.

7.4 Estimation Using Simulation

When the board temperature is not known, a thermal simulation of the application is needed. The simple two-resistor model can be used with the thermal simulation of the application [2], or a more accurate and complex model of the package can be used in the thermal simulation.

7.5 Experimental Determination

To determine the junction temperature of the device in the application after prototypes are available, the thermal characterization parameter (Ψ_{JT}) can be used to determine the junction temperature with a measurement of the temperature at the top center of the package case using the following equation:

$$T_{J} = T_{T} + (\Psi_{JT} \times P_{D})$$



Layout Practices

where:

 Ψ_{IT} = thermal characterization parameter

 T_T = thermocouple temperature on top of package

 P_D = power dissipation in package

The thermal characterization parameter is measured per JEDEC JESD51-2 specification using a 40 gauge type T thermocouple epoxied to the top center of the package case. The thermocouple should be positioned so that the thermocouple junction rests on the package. A small amount of epoxy is placed over the thermocouple junction and over 1 mm of wire extending from the junction. The thermocouple wire is placed flat against the package case to avoid measurement errors caused by cooling effects of the thermocouple wire.

7.6 References

Semiconductor Equipment and Materials International (415) 964-5111

805 East Middlefield Rd. Mountain View, CA 94043

MIL-SPEC and EIA/JESD (JEDEC) Specifications 800-854-7179 or (Available from Global Engineering Documents) 303-397-7956

JEDEC Specifications http://www.jedec.org

1. C.E. Triplett and B. Joiner, "An Experimental Characterization of a 272 PBGA Within an Automotive Engine Controller Module," Proceedings of SemiTherm, San Diego, 1998, pp. 47–54.

2. B. Joiner and V. Adams, "Measurement and Simulation of Junction to Board Thermal Resistance and Its Application in Thermal Modeling," Proceedings of SemiTherm, San Diego, 1999, pp. 212–220.

8 Layout Practices

Each V_{DD} pin on the MPC860 should be provided with a low-impedance path to the board's supply. Each GND pin should likewise be provided with a low-impedance path to ground. The power supply pins drive distinct groups of logic on the chip. The V_{DD} power supply should be bypassed to ground using at least four 0.1 μ F-bypass capacitors located as close as possible to the four sides of the package. The capacitor leads and associated printed circuit traces connecting to chip V_{DD} and GND should be kept to less than half an inch per capacitor lead. A four-layer board employing two inner layers as V_{CC} and GND planes is recommended.

All output pins on the MPC860 have fast rise and fall times. Printed circuit (PC) trace interconnection length should be minimized in order to minimize undershoot and reflections caused by these fast output switching times. This recommendation particularly applies to the address and data buses. Maximum PC trace lengths of 6 inches are recommended. Capacitance calculations should consider all device loads as well as parasitic capacitances due to the PC traces. Attention to proper PCB layout and bypassing becomes especially critical in systems with higher capacitive loads because these loads create higher transient currents in the $V_{\rm CC}$ and GND circuits. Pull up all unused inputs or signals that will be inputs during reset. Special care should be taken to minimize the noise levels on the PLL supply pins.



Table 7 provides the bus operation timing for the MPC860 at 33, 40, 50, and 66 MHz.

The maximum bus speed supported by the MPC860 is 66 MHz. Higher-speed parts must be operated in half-speed bus mode (for example, an MPC860 used at 80 MHz must be configured for a 40-MHz bus).

The timing for the MPC860 bus shown assumes a 50-pF load for maximum delays and a 0-pF load for minimum delays.

Table 7. Bus Operation Timings

Norma	Observatoristis	33	MHz	40 [ИНz	50 I	ИНz	66 I	ИНz	11!4
Num	Characteristic	Min	Max	Min	Max	Min	Max	Min	Max	Unit
B1	CLKOUT period	30.30	30.30	25.00	30.30	20.00	30.30	15.15	30.30	ns
B1a	EXTCLK to CLKOUT phase skew (EXTCLK > 15 MHz and MF <= 2)	-0.90	0.90	-0.90	0.90	-0.90	0.90	-0.90	0.90	ns
B1b	EXTCLK to CLKOUT phase skew (EXTCLK > 10 MHz and MF < 10)	-2.30	2.30	-2.30	2.30	-2.30	2.30	-2.30	2.30	ns
B1c	CLKOUT phase jitter (EXTCLK > 15 MHz and MF <= 2) ¹	-0.60	0.60	-0.60	0.60	-0.60	0.60	-0.60	0.60	ns
B1d	CLKOUT phase jitter ¹	-2.00	2.00	-2.00	2.00	-2.00	2.00	-2.00	2.00	ns
B1e	CLKOUT frequency jitter (MF < 10) ¹	_	0.50	_	0.50	_	0.50	_	0.50	%
B1f	CLKOUT frequency jitter (10 < MF < 500) ¹	_	2.00	_	2.00	_	2.00	_	2.00	%
B1g	CLKOUT frequency jitter (MF > 500) ¹	_	3.00	_	3.00	_	3.00	_	3.00	%
B1h	Frequency jitter on EXTCLK ²	_	0.50	_	0.50	_	0.50	_	0.50	%
B2	CLKOUT pulse width low	12.12	_	10.00	_	8.00	_	6.06	_	ns
В3	CLKOUT width high	12.12	_	10.00	_	8.00	_	6.06	_	ns
B4	CLKOUT rise time ³	_	4.00	_	4.00	_	4.00	_	4.00	ns
B5 ³³	CLKOUT fall time ³	_	4.00	_	4.00	_	4.00	_	4.00	ns
B7	CLKOUT to A(0:31), BADDR(28:30), RD/WR, BURST, D(0:31), DP(0:3) invalid	7.58	_	6.25	_	5.00	_	3.80	_	ns
В7а	CLKOUT to TSIZ(0:1), REG, RSV, AT(0:3), BDIP, PTR invalid	7.58	_	6.25	_	5.00	_	3.80	_	ns
B7b	CLKOUT to \overline{BR} , \overline{BG} , FRZ, VFLS(0:1), VF(0:2) IWP(0:2), LWP(0:1), \overline{STS} invalid 4	7.58	_	6.25	_	5.00	_	3.80	_	ns
B8	CLKOUT to A(0:31), BADDR(28:30) RD/WR, BURST, D(0:31), DP(0:3) valid	7.58	14.33	6.25	13.00	5.00	11.75	3.80	10.04	ns
B8a	CLKOUT to TSIZ(0:1), REG, RSV, AT(0:3) BDIP, PTR valid	7.58	14.33	6.25	13.00	5.00	11.75	3.80	10.04	ns
B8b	CLKOUT to BR, BG, VFLS(0:1), VF(0:2), IWP(0:2), FRZ, LWP(0:1), STS valid ⁴	7.58	14.33	6.25	13.00	5.00	11.75	3.80	10.04	ns



Table 7. Bus Operation Timings (continued)

Num	Chavastavistis	33 I	MHz	40 I	ИНz	50 I	ИНz	66 1	ИНz	Heit
Num	Characteristic	Min	Max	Min	Max	Min	Max	Min	Max	Unit
В9	CLKOUT to A(0:31), BADDR(28:30), RD/WR, BURST, D(0:31), DP(0:3), TSIZ(0:1), REG, RSV, AT(0:3), PTR High-Z	7.58	14.33	6.25	13.00	5.00	11.75	3.80	10.04	ns
B11	CLKOUT to TS, BB assertion	7.58	13.58	6.25	12.25	5.00	11.00	3.80	11.29	ns
B11a	CLKOUT to TA, BI assertion (when driven by the memory controller or PCMCIA interface)	2.50	9.25	2.50	9.25	2.50	9.25	2.50	9.75	ns
B12	CLKOUT to TS, BB negation	7.58	14.33	6.25	13.00	5.00	11.75	3.80	8.54	ns
B12a	CLKOUT to TA, BI negation (when driven by the memory controller or PCMCIA interface)	2.50	11.00	2.50	11.00	2.50	11.00	2.50	9.00	ns
B13	CLKOUT to TS, BB High-Z	7.58	21.58	6.25	20.25	5.00	19.00	3.80	14.04	ns
B13a	CLKOUT to TA, BI High-Z (when driven by the memory controller or PCMCIA interface)	2.50	15.00	2.50	15.00	2.50	15.00	2.50	15.00	ns
B14	CLKOUT to TEA assertion	2.50	10.00	2.50	10.00	2.50	10.00	2.50	9.00	ns
B15	CLKOUT to TEA High-Z	2.50	15.00	2.50	15.00	2.50	15.00	2.50	15.00	ns
B16	TA, BI valid to CLKOUT (setup time)	9.75	_	9.75	_	9.75	_	6.00	_	ns
B16a	TEA, KR, RETRY, CR valid to CLKOUT (setup time)	10.00	_	10.00	_	10.00	_	4.50	_	ns
B16b	$\overline{BB}, \overline{BG}, \overline{BR},$ valid to CLKOUT (setup time) 5	8.50	_	8.50	_	8.50	_	4.00	_	ns
B17	CLKOUT to \overline{TA} , \overline{TEA} , \overline{BI} , \overline{BB} , \overline{BG} , \overline{BR} valid (hold time)	1.00	_	1.00	_	1.00	_	2.00	_	ns
B17a	CLKOUT to KR, RETRY, CR valid (hold time)	2.00	_	2.00	_	2.00	_	2.00	_	ns
B18	D(0:31), DP(0:3) valid to CLKOUT rising edge (setup time) ⁶	6.00	_	6.00	_	6.00	_	6.00	_	ns
B19	CLKOUT rising edge to D(0:31), DP(0:3) valid (hold time) ⁶	1.00	_	1.00	_	1.00	_	2.00	_	ns
B20	D(0:31), DP(0:3) valid to CLKOUT falling edge (setup time) ⁷	4.00	_	4.00	_	4.00	_	4.00	_	ns
B21	CLKOUT falling edge to D(0:31), DP(0:3) valid (hold time) ⁷	2.00	_	2.00	_	2.00	_	2.00	_	ns
B22	CLKOUT rising edge to $\overline{\text{CS}}$ asserted GPCM ACS = 00	7.58	14.33	6.25	13.00	5.00	11.75	3.80	10.04	ns
B22a	CLKOUT falling edge to $\overline{\text{CS}}$ asserted GPCM ACS = 10, TRLX = 0	_	8.00	_	8.00	_	8.00	_	8.00	ns
B22b	CLKOUT falling edge to $\overline{\text{CS}}$ asserted GPCM ACS = 11, TRLX = 0, EBDF = 0	7.58	14.33	6.25	13.00	5.00	11.75	3.80	10.54	ns
B22c	CLKOUT falling edge to $\overline{\text{CS}}$ asserted GPCM ACS = 11, TRLX = 0, EBDF = 1	10.86	17.99	8.88	16.00	7.00	14.13	5.18	12.31	ns



Table 7. Bus Operation Timings (continued)

N	Observatoristis	33 I	MHz	40 I	MHz	50 MHz 66 MHz	ИНz	11!4		
Num	Characteristic	Min	Max	Min	Max	Min	Max	Min	Max	Unit
B23	CLKOUT rising edge to $\overline{\text{CS}}$ negated GPCM read access, GPCM write access ACS = 00, TRLX = 0, and CSNT = 0	2.00	8.00	2.00	8.00	2.00	8.00	2.00	8.00	ns
B24	A(0:31) and BADDR(28:30) to \overline{CS} asserted GPCM ACS = 10, TRLX = 0	5.58	_	4.25	_	3.00	_	1.79	_	ns
B24a	A(0:31) and BADDR(28:30) to \overline{CS} asserted GPCM ACS = 11, TRLX = 0	13.15	_	10.50	_	8.00	_	5.58	_	ns
B25	CLKOUT rising edge to \overline{OE} , \overline{WE} (0:3) asserted	_	9.00	_	9.00	_	9.00	_	9.00	ns
B26	CLKOUT rising edge to OE negated	2.00	9.00	2.00	9.00	2.00	9.00	2.00	9.00	ns
B27	A(0:31) and BADDR(28:30) to \overline{CS} asserted GPCM ACS = 10, TRLX = 1	35.88	_	29.25	_	23.00	_	16.94	_	ns
B27a	A(0:31) and BADDR(28:30) to \overline{CS} asserted GPCM ACS = 11, TRLX = 1	43.45	_	35.50	_	28.00	_	20.73	_	ns
B28	CLKOUT rising edge to $\overline{\text{WE}}(0:3)$ negated GPCM write access CSNT = 0	_	9.00	_	9.00	_	9.00	_	9.00	ns
B28a	CLKOUT falling edge to $\overline{WE}(0:3)$ negated GPCM write access TRLX = 0, 1, CSNT = 1, EBDF = 0	7.58	14.33	6.25	13.00	5.00	11.75	3.80	10.54	ns
B28b	CLKOUT falling edge to $\overline{\text{CS}}$ negated GPCM write access TRLX = 0, 1, CSNT = 1, ACS = 10, or ACS = 11, EBDF = 0	_	14.33	_	13.00	_	11.75	_	10.54	ns
B28c	CLKOUT falling edge to WE(0:3) negated GPCM write access TRLX = 0, 1, CSNT = 1 write access TRLX = 0, CSNT = 1, EBDF = 1	10.86	17.99	8.88	16.00	7.00	14.13	5.18	12.31	ns
B28d	CLKOUT falling edge to \overline{CS} negated GPCM write access TRLX = 0, 1, CSNT = 1, ACS = 10, or ACS = 11, EBDF = 1	_	17.99	_	16.00	_	14.13	_	12.31	ns
B29	WE(0:3) negated to D(0:31), DP(0:3) High-Z GPCM write access CSNT = 0, EBDF = 0	5.58	_	4.25	_	3.00	_	1.79	_	ns
B29a	WE(0:3) negated to D(0:31), DP(0:3) High-Z GPCM write access, TRLX = 0, CSNT = 1, EBDF = 0	13.15	_	10.5	_	8.00	_	5.58	_	ns
B29b	CS negated to D(0:31), DP(0:3), High-Z GPCM write access, ACS = 00, TRLX = 0, 1, and CSNT = 0	5.58		4.25		3.00		1.79	_	ns
B29c	CS negated to D(0:31), DP(0:3) High-Z GPCM write access, TRLX = 0, CSNT = 1, ACS = 10, or ACS = 11, EBDF = 0	13.15	_	10.5	_	8.00	_	5.58	_	ns



Table 7. Bus Operation Timings (continued)

Nivers	Chayantayintin	33 MHz 40		40 I	ИНz	50 I	50 MHz 66 M		ИHz	11:4
Num	Characteristic	Min	Max	Min	Max	Min	Max	Min	Max	Unit
B29d	WE(0:3) negated to D(0:31), DP(0:3) High-Z GPCM write access, TRLX = 1, CSNT = 1, EBDF = 0	43.45	_	35.5	_	28.00	_	20.73		ns
B29e	CS negated to D(0:31), DP(0:3) High-Z GPCM write access, TRLX = 1, CSNT = 1, ACS = 10, or ACS = 11, EBDF = 0	43.45	_	35.5	_	28.00	_	29.73		ns
B29f	WE(0:3) negated to D(0:31), DP(0:3) High-Z GPCM write access, TRLX = 0, CSNT = 1, EBDF = 1	8.86	_	6.88	_	5.00	_	3.18		ns
B29g	CS negated to D(0:31), DP(0:3) High-Z GPCM write access, TRLX = 0, CSNT = 1, ACS = 10, or ACS = 11, EBDF = 1	8.86		6.88		5.00	_	3.18	_	ns
B29h	WE(0:3) negated to D(0:31), DP(0:3) High-Z GPCM write access, TRLX = 1, CSNT = 1, EBDF = 1	38.67	_	31.38	_	24.50	_	17.83		ns
B29i	CS negated to D(0:31), DP(0:3) High-Z GPCM write access, TRLX = 1, CSNT = 1, ACS = 10, or ACS = 11, EBDF = 1	38.67	_	31.38	_	24.50	_	17.83		ns
B30	CS, WE(0:3) negated to A(0:31), BADDR(28:30) invalid GPCM write access ⁸	5.58	_	4.25	_	3.00	_	1.79	_	ns
B30a	WE(0:3) negated to A(0:31), BADDR(28:30) invalid GPCM, write access, TRLX = 0, CSNT = 1, CS negated to A(0:31) invalid GPCM write access, TRLX = 0, CSNT = 1 ACS = 10, or ACS = 11, EBDF = 0	13.15	_	10.50	_	8.00	_	5.58	_	ns
B30b	WE(0:3) negated to A(0:31), invalid GPCM BADDR(28:30) invalid GPCM write access, TRLX = 1, CSNT = 1. CS negated to A(0:31), Invalid GPCM, write access, TRLX = 1, CSNT = 1, ACS = 10, or ACS = 11, EBDF = 0	43.45	_	35.50	_	28.00	_	20.73	ı	ns
B30c	WE(0:3) negated to A(0:31), BADDR(28:30) invalid GPCM write access, TRLX = 0, CSNT = 1. $\overline{\text{CS}}$ negated to A(0:31) invalid GPCM write access, TRLX = 0, CSNT = 1, ACS = 10, ACS = 11, EBDF = 1	8.36	_	6.38	_	4.50	_	2.68		ns
B30d	WE(0:3) negated to A(0:31), BADDR(28:30) invalid GPCM write access, TRLX = 1, CSNT =1. \overline{CS} negated to A(0:31) invalid GPCM write access TRLX = 1, CSNT = 1, ACS = 10, or ACS = 11, EBDF = 1	38.67	_	31.38	_	24.50	_	17.83	_	ns
B31	CLKOUT falling edge to CS valid—as requested by control bit CST4 in the corresponding word in UPM	1.50	6.00	1.50	6.00	1.50	6.00	1.50	6.00	ns



Table 7. Bus Operation Timings (continued)

Num	Characteristic	33 MHz		40 MHz		50 MHz		66 MHz		
		Min	Max	Min	Max	Min	Max	Min	Max	Unit
B31a	CLKOUT falling edge to CS valid—as requested by control bit CST1 in the corresponding word in UPM	7.58	14.33	6.25	13.00	5.00	11.75	3.80	10.54	ns
B31b	CLKOUT rising edge to CS valid—as requested by control bit CST2 in the corresponding word in UPM	1.50	8.00	1.50	8.00	1.50	8.00	1.50	8.00	ns
B31c	CLKOUT rising edge to CS valid—as requested by control bit CST3 in the corresponding word in UPM	7.58	14.33	6.25	13.00	5.00	11.75	3.80	10.04	ns
B31d	CLKOUT falling edge to $\overline{\text{CS}}$ valid—as requested by control bit CST1 in the corresponding word in UPM, EBDF = 1	13.26	17.99	11.28	16.00	9.40	14.13	7.58	12.31	ns
B32	CLKOUT falling edge to BS valid—as requested by control bit BST4 in the corresponding word in UPM	1.50	6.00	1.50	6.00	1.50	6.00	1.50	6.00	ns
B32a	CLKOUT falling edge to BS valid—as requested by control bit BST1 in the corresponding word in UPM, EBDF = 0	7.58	14.33	6.25	13.00	5.00	11.75	3.80	10.54	ns
B32b	CLKOUT rising edge to BS valid—as requested by control bit BST2 in the corresponding word in UPM	1.50	8.00	1.50	8.00	1.50	8.00	1.50	8.00	ns
B32c	CLKOUT rising edge to BS valid—as requested by control bit BST3 in the corresponding word in UPM	7.58	14.33	6.25	13.00	5.00	11.75	3.80	10.54	ns
B32d	CLKOUT falling edge to BS valid—as requested by control bit BST1 in the corresponding word in UPM, EBDF = 1	13.26	17.99	11.28	16.00	9.40	14.13	7.58	12.31	ns
B33	CLKOUT falling edge to GPL valid—as requested by control bit GxT4 in the corresponding word in UPM	1.50	6.00	1.50	6.00	1.50	6.00	1.50	6.00	ns
B33a	CLKOUT rising edge to GPL valid—as requested by control bit GxT3 in the corresponding word in UPM	7.58	14.33	6.25	13.00	5.00	11.75	3.80	10.54	ns
B34	A(0:31), BADDR(28:30), and D(0:31) to $\overline{\text{CS}}$ valid—as requested by control bit CST4 in the corresponding word in UPM	5.58	_	4.25	_	3.00	_	1.79	_	ns
B34a	A(0:31), BADDR(28:30), and D(0:31) to $\overline{\text{CS}}$ valid—as requested by control bit CST1 in the corresponding word in UPM	13.15	_	10.50	_	8.00	_	5.58	_	ns
B34b	A(0:31), BADDR(28:30), and D(0:31) to $\overline{\text{CS}}$ valid—as requested by control bit CST2 in the corresponding word in UPM	20.73	_	16.75	_	13.00	_	9.36	_	ns



Table 7. Bus Operation Timings (continued)

Num	Characteristic	33 MHz		40 MHz		50 MHz		66 MHz		I I m i A
		Min	Max	Min	Max	Min	Max	Min	Max	Unit
B35	A(0:31), BADDR(28:30) to $\overline{\text{CS}}$ valid—as requested by control bit BST4 in the corresponding word in UPM	5.58	_	4.25	_	3.00	_	1.79	_	ns
B35a	A(0:31), BADDR(28:30), and D(0:31) to \overline{BS} valid—as requested by control bit BST1 in the corresponding word in UPM	13.15	_	10.50	_	8.00	_	5.58	_	ns
B35b	A(0:31), BADDR(28:30), and D(0:31) to BS valid—as requested by control bit BST2 in the corresponding word in UPM	20.73	_	16.75	_	13.00	_	9.36	_	ns
B36	A(0:31), BADDR(28:30), and D(0:31) to GPL valid—as requested by control bit GxT4 in the corresponding word in UPM	5.58	_	4.25	_	3.00	_	1.79	_	ns
B37	UPWAIT valid to CLKOUT falling edge ⁹	6.00	_	6.00	_	6.00	_	6.00	_	ns
B38	CLKOUT falling edge to UPWAIT valid ⁹	1.00	_	1.00	_	1.00	_	1.00	_	ns
B39	AS valid to CLKOUT rising edge ¹⁰	7.00	_	7.00	_	7.00	_	7.00	_	ns
B40	A(0:31), TSIZ(0:1), RD/WR, BURST, valid to CLKOUT rising edge	7.00	_	7.00	_	7.00	_	7.00	_	ns
B41	TS valid to CLKOUT rising edge (setup time)	7.00	_	7.00	_	7.00	_	7.00	_	ns
B42	CLKOUT rising edge to TS valid (hold time)	2.00	_	2.00	_	2.00	_	2.00	_	ns
B43	AS negation to memory controller signals negation	_	TBD	_	TBD	_	TBD	_	TBD	ns

¹ Phase and frequency jitter performance results are only valid if the input jitter is less than the prescribed value.

² If the rate of change of the frequency of EXTAL is slow (that is, it does not jump between the minimum and maximum values in one cycle) or the frequency of the jitter is fast (that is, it does not stay at an extreme value for a long time) then the maximum allowed jitter on EXTAL can be up to 2%.

³ The timings specified in B4 and B5 are based on full strength clock.

⁴ The timing for \overline{BR} output is relevant when the MPC860 is selected to work with external bus arbiter. The timing for \overline{BG} output is relevant when the MPC860 is selected to work with internal bus arbiter.

⁵ The timing required for \overline{BR} input is relevant when the MPC860 is selected to work with internal bus arbiter. The timing for \overline{BG} input is relevant when the MPC860 is selected to work with external bus arbiter.

⁶ The D(0:31) and DP(0:3) input timings B18 and B19 refer to the rising edge of the CLKOUT in which the TA input signal is asserted.

The D(0:31) and DP(0:3) input timings B20 and B21 refer to the falling edge of the CLKOUT. This timing is valid only for read accesses controlled by chip-selects under control of the UPM in the memory controller, for data beats where DLT3 = 1 in the UPM RAM words. (This is only the case where data is latched on the falling edge of CLKOUT.)

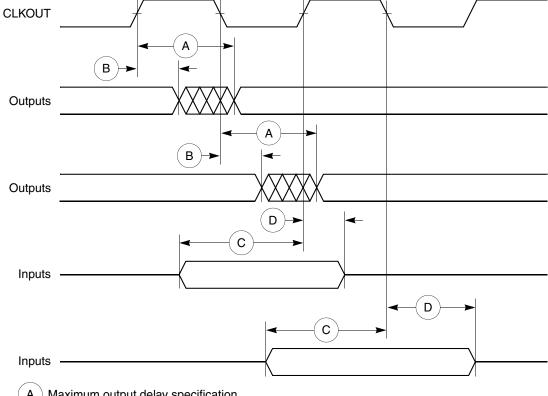
⁸ The timing B30 refers to \overline{CS} when ACS = 00 and to \overline{WE} (0:3) when CSNT = 0.

⁹ The signal UPWAIT is considered asynchronous to the CLKOUT and synchronized internally. The timings specified in B37 and B38 are specified to enable the freeze of the UPM output signals as described in Figure 18.

¹⁰ The $\overline{\text{AS}}$ signal is considered asynchronous to the CLKOUT. The timing B39 is specified in order to allow the behavior specified in Figure 21.



Figure 3 is the control timing diagram.



- Maximum output delay specification.
- Minimum output hold time.
- Minimum input setup time specification.
- Minimum input hold time specification.

Figure 3. Control Timing

Figure 4 provides the timing for the external clock.

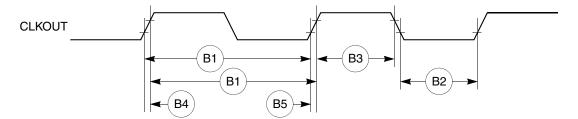


Figure 4. External Clock Timing



Figure 5 provides the timing for the synchronous output signals.

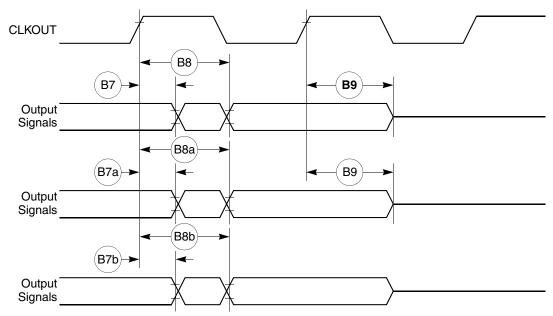


Figure 5. Synchronous Output Signals Timing

Figure 6 provides the timing for the synchronous active pull-up and open-drain output signals.

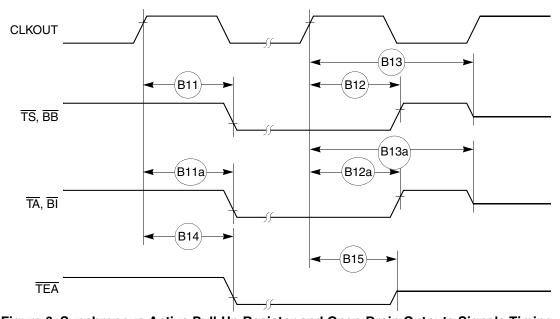


Figure 6. Synchronous Active Pull-Up Resistor and Open-Drain Outputs Signals Timing



Figure 7 provides the timing for the synchronous input signals.

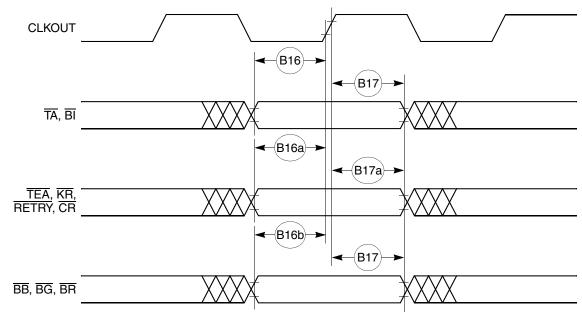


Figure 7. Synchronous Input Signals Timing

Figure 8 provides normal case timing for input data. It also applies to normal read accesses under the control of the UPM in the memory controller.

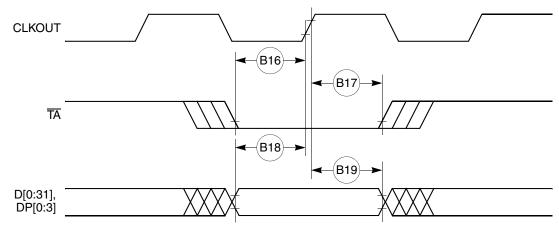


Figure 8. Input Data Timing in Normal Case



Figure 9 provides the timing for the input data controlled by the UPM for data beats where DLT3 = 1 in the UPM RAM words. (This is only the case where data is latched on the falling edge of CLKOUT.)

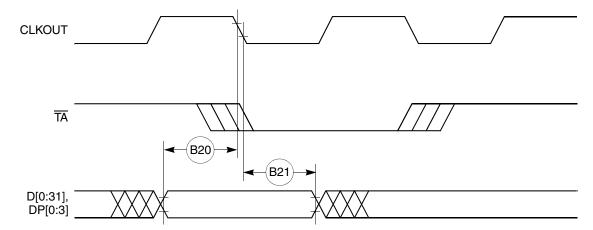


Figure 9. Input Data Timing when Controlled by UPM in the Memory Controller and DLT3 = 1

Figure 10 through Figure 13 provide the timing for the external bus read controlled by various GPCM factors.

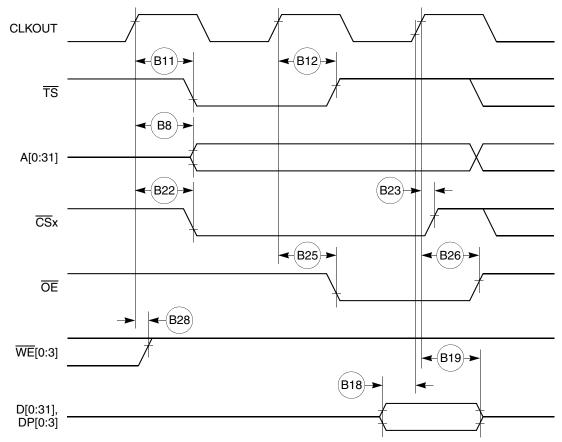


Figure 10. External Bus Read Timing (GPCM Controlled—ACS = 00)



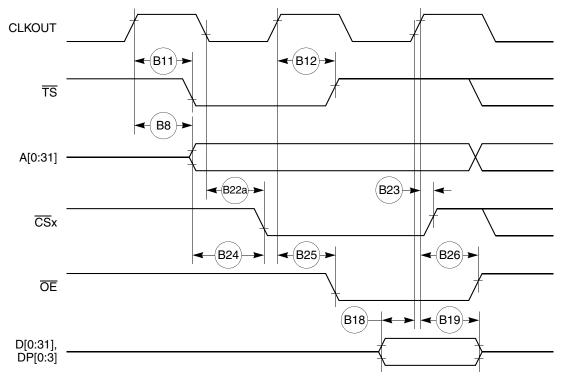


Figure 11. External Bus Read Timing (GPCM Controlled—TRLX = 0, ACS = 10)

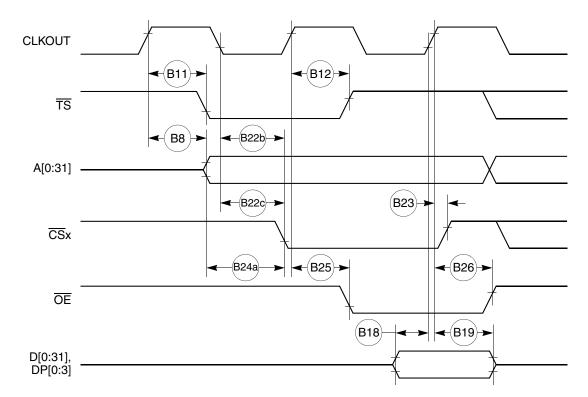


Figure 12. External Bus Read Timing (GPCM Controlled—TRLX = 0, ACS = 11)